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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(Use several sheets if necessary)</small>		Applicant Lei WANG			
		Filing Date December 18, 2001		Group 2131	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
15	1	L. WANG et al., "Experimental Results of Face Description based on the 2 nd order Eigenface Method," ISO/IEC JTC1/SC29/WG11 MPEG2000/M6001, May 2000, pp. 1-35.					
	2	L. WANG et al., "New Proposal for Face Feature Description," ISO/IEC JTC1/SC29/WG11 MPEG2000/M5750, March 2000, pp. 1-6.					
	3	CD 15938-3 MPEG-7 Multimedia Content Description Interface-Part 3 Visual," ISO/IEC JTC1/SC29/WG11/W3703, October 2000, pp. 1-183.					
	4	T. SHAKUNAGA et al., "Decomposed Eigenface for Face Recognition Under Various Lighting Conditions," Proceedings 2001 IEEE Conference on Computer Vision and Pattern Recognition, 2001, pp. 864-871.					
	5	H.-C. KIM et al., "Proposal for Face Description Using 2 nd -order PCA Mixture Model," ISO/IEC JTC1/SC29/WG11 MPEG2001/M7286, July 2001, pp. 1-8.					
	6	T. KAMEI et al., "Extension of the Face Recognition Descriptor Using a Confidence Factor," ISO/IEC JTC1/SC29/WG11 MPEG2001/M7689, December 2001, pp. 1-9.					
	7	H.-C. KIM et al., "Face Retrieval Using 1 st - and 2 nd -order PCA Mixture Model," Proceedings 2002 International Conference on Image Processing, 2002, pp. 605-608.					
	9	M.-S. KIM et al., "Face Recognition Using the Embedded HMM with Second-order Block-specific Observations," Pattern Recognition, Vol. 36, 2003, pp. 2723-2735.					

EXAMINER	<i>John J. Tracy</i>	DATE CONSIDERED	<i>11/9/04</i>
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